

B1
capacity as follows: C_c/n , and the internal division point determining step is the step of determining the one or more internal points of division so that the coupling capacity between each of the plurality of wire segment and the aggressor is equal to the target coupling capacity C_c/n .

Please replace the paragraph beginning at page 10, line 14, with the following:

B2
In accordance with another aspect of the present invention, the buffer number determining step is the step of, when the amount of glitch is V and a predetermined value is V_{max} , calculating the smallest integer number n which satisfies a following relationship: $V/n \leq V_{max}$. By setting V_{max} to a target for the amount of glitch (if the amount of glitch to be caused is equal to or less than the target, it can be assumed that the glitch error is eliminated), the number of buffers to be inserted is $(n-1)$. Thus, a smaller number of buffers to be inserted can be estimated.

Please replace the paragraph beginning at page 14, line 7, with the following:

B3
A description will be made as to how the circuit is modified using the circuit modification method of the present embodiment when it is determined that a glitch caused in the wire 1 (referred to as victim 1 hereafter) by signal change in the other wire 2 (referred to as aggressor 2 hereafter) which is an aggressor causes a glitch error, with reference to a flow chart of Fig. 5(a).

Please replace the paragraph beginning at page 15, line 13, with the following:

BY
Next, it is determined, in step ST2, whether the amount V of glitch is equal to or less than a given value V_{err} or not. The value V_{err} is predetermined in such a manner that if the amount of glitch is greater than the value V_{err} , it can be determined that a glitch error occurs. If $V \leq V_{err}$, it is determined that the aggressor 2 does not cause any glitch error in the victim 1, and no circuit modification process such as insertion of one or more buffers into the victim is carried out. If $V > V_{err}$, it is determined that there causes a glitch error, and step ST3 is performed.

Please replace the paragraph beginning at page 16, line 18, with the following:

BS
In step ST31, a certain amount V_{max} of glitch is predetermined, and the smallest possible integer n which satisfies the following relationship: $V/n \leq V_{max}$ is calculated. The integer n is the number by which the victim 1 is to be divided into wire segments, and the integer $(n-1)$ is therefore equal to the number of buffers to be inserted into the victim 1. The value V_{max} is a target amount of glitch which is defined as a target for the amount of glitch. If the amount of glitch to be caused is equal to or less than V_{max} , it can be assumed that the glitch error is eliminated. The value V_{max} is predetermined so that it simply satisfies the following relationship $V_{max} \leq V_{err}$. Since the relationship of $V_{max} \leq V_{err} < V$ is established, the number n by which the victim 1 is to be divided is calculated and is an integer of 2 or more, and the number of buffers to be inserted into the victim is calculated and is 1 or more.